

STQ3N45K3-AP

Datasheet - production data

N-channel 450 V - 3.3 Ω typ., 0.6 A Zener-protected, SuperMESH3[™] Power MOSFET in a TO-92 package

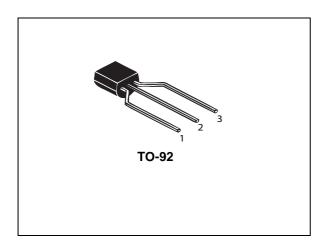
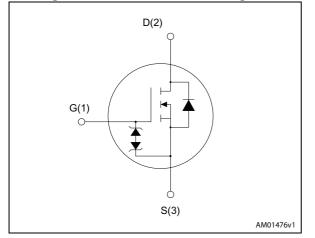


Figure 1. Internal schematic diagram



Features

Order code	V _{DSS}	R _{DS(on)} max	I _D	Pw
STQ3N45K3-AP	450 V	<4Ω	0.6 A	3 W

- 100% avalanche tested
- Extremely high dv/dt capability
- Gate charge minimized
- Very low intrinsic capacitance
- Improved diode reverse recovery characteristics
- Zener-protected

Applications

• Switching applications

Description

This SuperMESH3[™] Power MOSFET is the result of improvements applied to STMicroelectronics' SuperMESH[™] technology, combined with a new optimized vertical structure. This device boasts an extremely low on-resistance, superior dynamic performance and high avalanche capability, rendering it suitable for the most demanding applications.

Table 1. Device summary

Order code	Marking	Package	Packaging
STQ3N45K3-AP	3N45K3	TO-92	Ammopak

DocID024887 Rev 1

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1

Electrical ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage ($V_{GS} = 0$)	450	V
V _{GS}	Gate- source voltage	± 30	V
I _D	Drain current (continuous) at $T_C = 25 \text{ °C}$	0.6	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	2.4	А
P _{TOT}	Total dissipation at $T_C = 25 \text{ °C}$	3	W
I _{AR} ⁽²⁾	Avalanche current, repetitive or not-repetitive	0.6	А
E _{AS} ⁽³⁾	Single pulse avalanche energy (starting $T_j = 25^{\circ}C$, $I_D = I_{AR}$, $V_{DD} = 50V$)	45	mJ
dv/dt ⁽⁴⁾	Peak diode recovery voltage slope	12	V/ns
Vesd(g-s)	G-S ESD (HBM C = 100 pF, R = 1.5 kΩ)	1000	V
T _{stg}	Storage temperature	-55 to 150	°C
Тj	Max. operating junction temperature	150	°C

Table 2. Absolute maximum ratings

1. Pulse width limited by safe operating area.

2. Pulse width limited by $T_{j max}$.

3. Starting $T_j = 25 \text{ °C}$, $I_D = I_{AR}$, $V_{DD} = 50 \text{ V}$.

4. $I_{SD} \leq 0.6 \text{ A}, \text{ di/dt} \leq 400 \text{ A/}\mu\text{s}, \text{V}_{DS} \text{ peak} \leq \text{V}_{(BR)DSS}, \text{V}_{DD} = 80\% \text{ V}_{(BR)DSS}.$

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-ambient	42	°C/W



2 Electrical characteristics

($T_C = 25$ °C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0	450			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 450 V V _{DS} = 450 V, T _C =125 °C			1 50	μA μA
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 20 V			± 10	μA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 50 \ \mu A$	3	3.75	4.5	V
R _{DS(on}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 0.6 A		3.3	4	Ω

Table 4	4. On	/off	states
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Table 5. Dynam	າເຕ

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit			
C _{iss}	Input capacitance		-	164	-	pF			
C _{oss}	Output capacitance	V _{DS} = 50 V, f = 1 MHz, V _{GS} = 0	-	17	-	pF			
C _{rss}	Reverse transfer capacitance		-	3	-	pF			
C _{o(tr)} ⁽¹⁾	Equivalent capacitance time related	$y_{1} = 0$ to $260 y_{1} y_{2} = 0$	-	13	-	pF			
C _{o(er)} ⁽²⁾	Equivalent capacitance energy related	$V_{DS} = 0$ to 360 V, $V_{GS} = 0$ -	-	18	-	pF			
R _G	Intrinsic gate resistance	f = 1 MHz open drain	-	8	-	Ω			
Qg	Total gate charge	V _{DD} = 360 V, I _D = 1.8 A,	-	9.5	-	nC			
Q _{gs}	Gate-source charge	V _{GS} = 10 V	-	2	-	nC			
Q _{gd}	Gate-drain charge	(see Figure 16)	-	6	-	nC			

1. $C_{oss eq.}$ time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

2. $C_{oss \ eq}$ energy related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}



Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit	
t _{d(on)}	Turn-on delay time		-	6.5	-	ns	
t _r	Rise time	V _{DD} = 225 V, I _D = 0.9 A, R _G = 4.7 Ω, V _{GS} = 10 V	-	5.4	-	ns	
t _{d(off)}	Turn-off-delay time	(see <i>Figure 15</i>)	-	17	-	ns	
t _f	Fall time		-	22	-	ns	

Table 6. Switching times

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		-		0.6	А
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		2.4	А
V _{SD} ⁽²⁾	Forward on voltage	$I_{SD} = 0.6 \text{ A}, V_{GS} = 0$	-		1.5	V
t _{rr}	Reverse recovery time		-	175		ns
Q _{rr}	Reverse recovery charge	I _{SD} = 1.8 A, di/dt = 100 A/μs V _{DD} = 60 V (see <i>Figure 20</i>)	-	550		nC
I _{RRM}	Reverse recovery current	$v_{\text{DD}} = 00 \text{ v} (\text{see Figure 20})$	-	6		А
t _{rr}	Reverse recovery time	I _{SD} = 1.8 A, di/dt = 100 A/µs	-	185		ns
Q _{rr}	Reverse recovery charge	V _{DD} = 60 V, T _j = 150 °C	-	600		nC
I _{RRM}	Reverse recovery current	(see Figure 20)	-	6.5		А

1. Pulse width limited by safe operating area.

2. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%.

Table 8. Gate-source Zener c	diode
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Symbol	Parameter	Test conditions	Min	Тур	Max	Unit
V _{(BR)GSO}	Gate-source breakdown voltage	I_{GS} = ± 1 mA, I_{D} =0	30	-	-	V

The built-in back-to-back Zener diodes have been specifically designed to enhance not only the device's ESD capability, but also to make them capable of safely absorbing any voltage transients that may occasionally be applied from gate to source. In this respect, the Zener voltage is appropriate to achieve efficient and cost-effective protection of device integrity. The integrated Zener diodes thus eliminate the need for external components.



2.1 Electrical characteristics (curves)

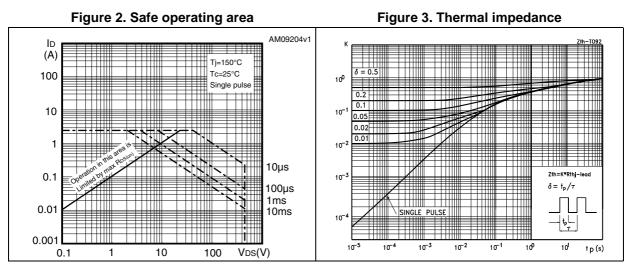
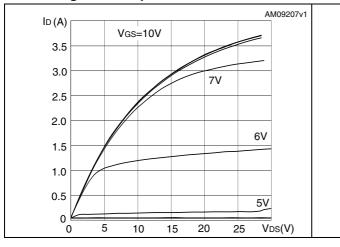


Figure 4. Output characteristics





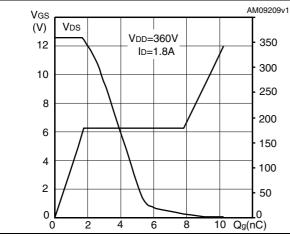


Figure 5. Transfer characteristics

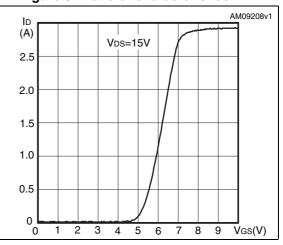
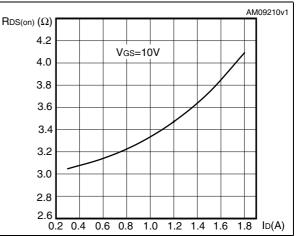
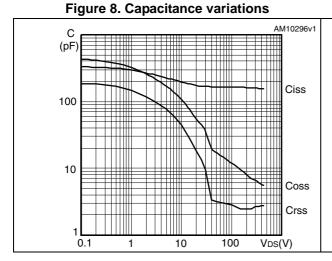
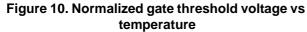


Figure 7. Static drain-source on resistance









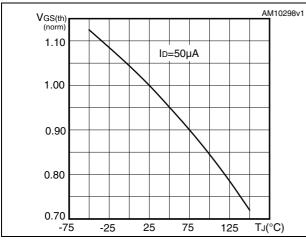
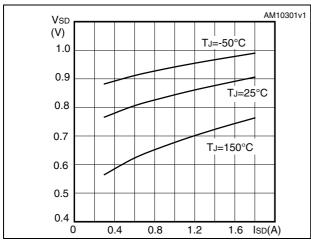
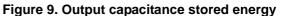


Figure 12. Source-drain diode forward characteristics





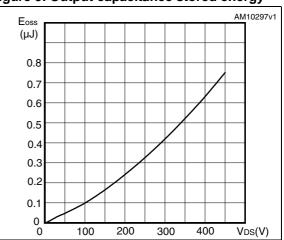


Figure 11. Normalized on-resistance vs temperature

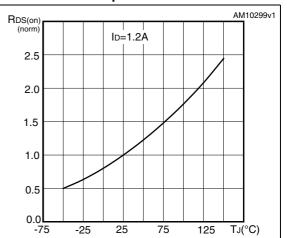
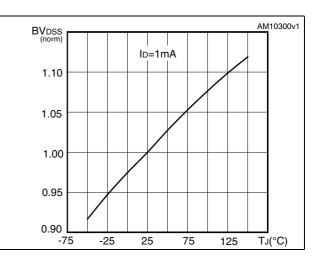


Figure 13. Normalized B_{VDSS} vs temperature





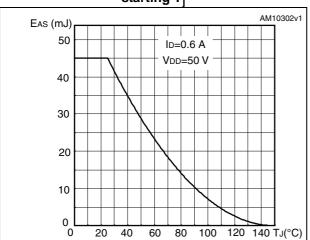


Figure 14. Maximum avalanche energy vs starting T_j

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Test circuits 3

Figure 15. Switching times test circuit for resistive load

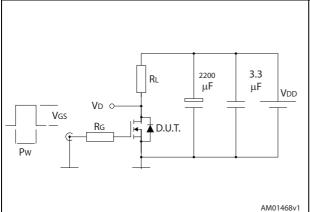


Figure 17. Test circuit for inductive load switching and diode recovery times

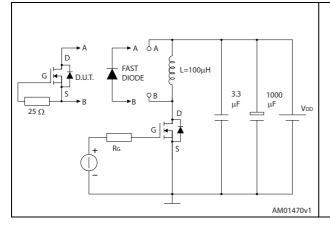
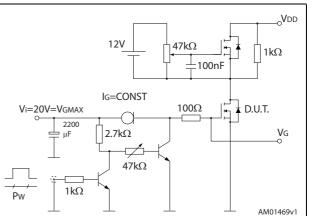


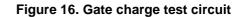
Figure 19. Unclamped inductive waveform

VD

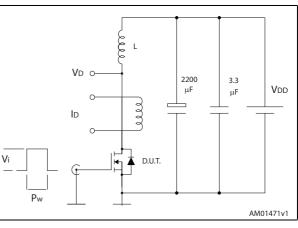
IDM

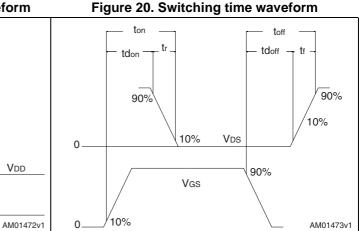
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V(BR)DSS



Vdd

Vdd

4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK[®] is an ST trademark.



D .	mm			
Dim.	Min.	Тур.	Max.	
A1			4.80	
Т			3.80	
T1			1.60	
T2			2.30	
d	0.45	0.47	0.48	
P0	12.50	12.70	12.90	
P2	5.65	6.35	7.05	
F1, F2	2.40	2.50	2.94	
F3	4.98	5.08	5.48	
delta H	-2.00		2.00	
W	17.50	18.00	19.00	
W0	5.5	6.00	6.5	
W1	8.50	9.00	9.25	
W2			0.50	
Н		18.50	21	
H3	0.5	1	2	
H0	15.50	16.00	18.8	
H1		25.0	27.0	
D0	3.80	4.00	4.20	
t			0.90	
L			11.00	
11	3.00			
delta P	-1.00		1.00	

Table 9. TO-92 ammopack mechanical data



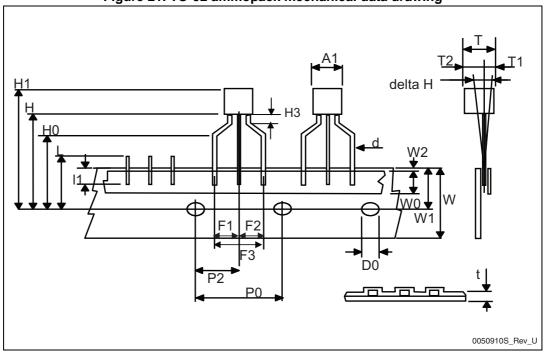


Figure 21. TO-92 ammopack mechanical data drawing



5 Revision history

Table 10.	Document	revision	history
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Date	Revision	Changes	
24-Jun-2013	in-2013 1 First release. Part number previously included in datasheet DocID17206		



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